## Application/Control No. Applicant(s)/Patent Under Reexamination 10/787,347 KIMURA, HAJIME Notice of References Cited Examiner Art Unit Page 1 of 1 2816 Hiep Nguyen **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY \* 01-2002 US-2002/0008543 Nasu et al. 326/83 Α US-2005/0052209 03-2005 327/170 В Jacobs et al. US-С US-D US-Е US-F US-G US-Н US-Ţ US-J Κ US-US-

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